

UNITED STATES PATENT AND TRADEMARK OFFICE

APPLICANT(S)	<i>Dimitry Shur</i>	GROUP ART UNIT:	2881
APPLN. NO.:	10/691,746	EXAMINER:	Johnston, Phillip A.
FILED:	10/22/2003		
TITLE:	SYSTEM AND METHOD FOR MEASURING OVERLAY ERRORS		

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

This paper is responsive to the Office Action dated July 31st 2006, having a shortened statutory period of three months expiring October 31st 2006 Further examination and reconsideration are respectfully requested.

FEES

No additional fees are believed to be owed in connection with this response.